

RADC/NBS International Workshop Moisture Measurement and Control for Microelectronics (IV), 1986

Session I, Chairman, A DerMarderosian Raytheon

Helium Leak Detector for Small Components

By L. E. Bergquist and S. R. Scherts (Martin Marietta Denver Aerospace) - Published in RL/NIST Moisture Workshop 1986, P6

Permissible Leak Rates and Moisture Ingress

By A. DerMarderosian (Raytheon) - Published in RL/NIST Moisture Workshop 1986, P15

The Negative Ion Detection (NID) Vapor Detection Technique: A Breakthrough in Gross Leak Detection

By B. Evan (WEB Technology) - Published in RL/NIST Moisture Workshop 1986, P47

Reusable Moisture Standard Development for Package gas Analysis

By R. F. Haack (California Institute of Technology / Jet Propulsion Laboratory) - Published in RL/NIST Moisture Workshop 1986, P62

Session II, Chairman, R. K. Lowry (Harris Semiconductor)

Moisture Process Control and Mass Spectrometer Correlations

By R. K. Lowry (Harris Semiconductor) - Published in RL/NIST Moisture Workshop 1986, P73

Laboratory Correlation and Survey Experiment: A Status Report

By B. A. Moore and D. Kane (RADC) - Published in RL/NIST Moisture Workshop 1986, P96

Accuracy and Reproducibility of the Mass Spectrometer / Carousel Method for Moisture Analysis

By L. J. Rigby (STC Technology Ltd., UK)

Presented by J. Pernicka (Pernicka Corp) - Published in RL/NIST Moisture Workshop 1986, P104

Session III, Chairman, S. D. Senturia (MIT)

New Failure Mechanisms in Temperature and Humidity Stress

By D. Y. Guan, T. F. Gukelberger, E. C. Cahoon, T. w. Joseph, J. M. Snowdon (IBM) - Published in RL/NIST Moisture Workshop 1986, P124

Studies of Moisture in Polyimide: A Summary

By S. D. Senturia (MIT) - Published in RL/NIST Moisture Workshop 1986, P128

Moisture Control in Hermetic Leadless Chip Carriers with Silver-Epoxy Die-Attach Adhesive

By D. R. Carley and R. W. Nearhoff (RCA) - Published in RL/NIST Moisture Workshop 1986, P138

Polymeric Materials for Moisture Protection of Medical Implants

By P. R. Troyk (IIT) - Published in RL/NIST Moisture Workshop 1986, P161

Session IV, Chairman, J. Mucha (AT&T)

Pin Selection Criteria for AC Conduction Technique

By N. K. Annamalai and E. C. Blackburn (RADC) and S.M.R. Islam (Clarkson University) - Published in RL/NIST Moisture Workshop 1986, P173

Evaluation of a Parasitic Charge-Spreading Transistor as a Moisture Sensor

By K. Hultén and Ö. Halberg (RIFA AB, Sweden) - Published in RL/NIST Moisture Workshop 1986, P189

Moisture Measurement by AC-Biased Surface Conductivity Sensors

By D. Kane and B. A. Moore (RADC) - Published in RL/NIST Moisture Workshop 1986, P198

Tunable Diode Laser Systems for Moisture Measurement Integrated Circuit Packages

By D. Wall, J. Sproul, and A. Mantz (Spectra Physics) - Published in RL/NIST Moisture Workshop 1986, P214

Using Panametrics Mini-Mod Moisture Sensors for Moisture Measurements Inside Sealed Microelectronic Packages

By D. Pinsky (Raytheon Co.) - Published in RL/NIST Moisture Workshop 1986, P254

Aluminum Oxide Sensor: A Tutorial Update

By V. Fong (Panametrics) - Published in RL/NIST Moisture Workshop 1986, P276

Session V, Chairman, P. Schuessler (IBM)

Reliable Plastic ICs for Automotive Electronics

By R. J. Straub (Delco Electronics) - Published in RL/NIST Moisture Workshop 1986, P277

A Test Program to Assess Reliability of Plastic Packages and Gel Coatings for Military Environments

By E. C. Blackburn and D. Kane (RADC) - Published in RL/NIST Moisture Workshop 1986, P290

Moisture Monitor for Plastic Packaged Integrated Circuits

By H. L. Blaz (Harris Semiconductor) Presented by R. K. Lowry (Harris Semiconductor) - Published in RL/NIST Moisture Workshop 1986, P298

High Reliability Molded Plastic Packaging Through a Systematic Approach

By L. Liang (Fairchild Semiconductors) - Published in RL/NIST Moisture Workshop 1986, P307

High Lead Count / High Reliability Plastic Packaging: Issues and Approaches

By G. Pitts (MCC) - Published in RL/NIST Moisture Workshop 1986, P319